Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.2GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8547vtatgb

Table 1. Absolute Maximum Ratings [1] (continued)

Characteristic	Symbol	Max Value	Unit	Notes
Storage temperature range	T_{STG}	–55 to 150	°C	—

Notes:

1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. The –0.3 to 2.75 V range is for DDR and –0.3 to 1.98 V range is for DDR2.
3. The 3.63 V maximum is only supported when the port is configured in GMII, MII, RMII, or TBI modes; otherwise the 2.75 V maximum applies. See Section 8.2, "FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications," for details on the recommended operating conditions per protocol.
4. $(M,L,O)V_{IN}$ may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

2.1.2   Recommended Operating Conditions

The following table provides the recommended operating conditions for this device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic		Symbol	Recommended Value	Unit	Notes
Core supply voltage		V_{DD}	1.1 V ± 55 mV	V	—
PLL supply voltage		AV_{DD}	1.1 V ± 55 mV	V	1
Core power supply for SerDes transceivers		SV_{DD}	1.1 V ± 55 mV	V	—
Pad power supply for SerDes transceivers		XV_{DD}	1.1 V ± 55 mV	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	—
Three-speed Ethernet I/O voltage		LV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	4
		TV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	—	4
PCI/PCI-X, DUART, system control and power management, I^{2}C, Ethernet MII management, and JTAG I/O voltage		OV_{DD}	3.3 V ± 165 mV	V	3
Local bus I/O voltage		BV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	—
Input voltage	DDR and DDR2 DRAM signals	MV_{IN}	GND to GV_{DD}	V	2
	DDR and DDR2 DRAM reference	MV_{REF}	GND to $GV_{DD}/2$	V	2
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to LV_{DD} GND to TV_{DD}	V	4
	Local bus signals	BV_{IN}	GND to BV_{DD}	V	—
	PCI, DUART, SYSCLK, system control and power management, I^{2}C, Ethernet MII management, and JTAG signals	OV_{IN}	GND to OV_{DD}	V	3

4.3 eTSEC Gigabit Reference Clock Timing

The following table provides the eTSEC gigabit reference clocks (EC_GTX_CLK125) AC timing specifications for the device.

Table 6. EC_GTX_CLK125 AC Timing Specifications

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Notes
EC_GTX_CLK125 frequency	f_{G125}	—	125	—	MHz	—
EC_GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	
EC_GTX_CLK125 rise and fall time L/TVDD = 2.5 V L/TVDD = 3.3 V	t_{G125R}, t_{G125F}	—	—	0.75 1.0	ns	1
EC_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t_{G125H}/t_{G125}	45 47	—	55 53	%	2, 3

Notes:

1. Rise and fall times for EC_GTX_CLK125 are measured from 0.5 and 2.0 V for L/TV$_{DD}$ = 2.5 V, and from 0.6 and 2.7 V for L/TV$_{DD}$ = 3.3 V.

2. Timing is guaranteed by design and characterization.

3. EC_GTX_CLK125 is used to generate the GTX clock TSEC*n*_GTX_CLK for the eTSEC transmitter with 2% degradation. EC_GTX_CLK125 duty cycle can be loosened from 47/53% as long as the PHY device can tolerate the duty cycle generated by the TSEC*n*_ GTX_CLK. See Section 8.2.6, "RGMII and RTBI AC Timing Specifications," for duty cycle for 10Base-T and 100Base-T reference clock.

4.4 PCI/PCI-X Reference Clock Timing

When the PCI/PCI-X controller is configured for asynchronous operation, the reference clock for the PCI/PCI-x controller is not the SYSCLK input, but instead the PCI*n*_CLK. The following table provides the PCI/PCI-X reference clock AC timing specifications for the device.

Table 7. PCI*n*_CLK AC Timing Specifications

At recommended operating conditions (see Table 2) with OV$_{DD}$ = 3.3 V ± 165 mV.

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Notes
PCI*n*_CLK frequency	f_{PCICLK}	16	—	133	MHz	—
PCI*n*_CLK cycle time	t_{PCICLK}	7.5	—	60	ns	—
PCI*n*_CLK rise and fall time	t_{PCIKH}, t_{PCIKL}	0.6	1.0	2.1	ns	1, 2
PCI*n*_CLK duty cycle	$t_{PCIKHKL}/t_{PCICLK}$	40	—	60	%	2

Notes:

1. Rise and fall times for SYSCLK are measured at 0.6 and 2.7 V.

2. Timing is guaranteed by design and characterization.

NOTE

PLL bypass mode is required when LBIU frequency is at or below 83 MHz. When LBIU operates above 83 MHz, LBIU PLL is recommended to be enabled.

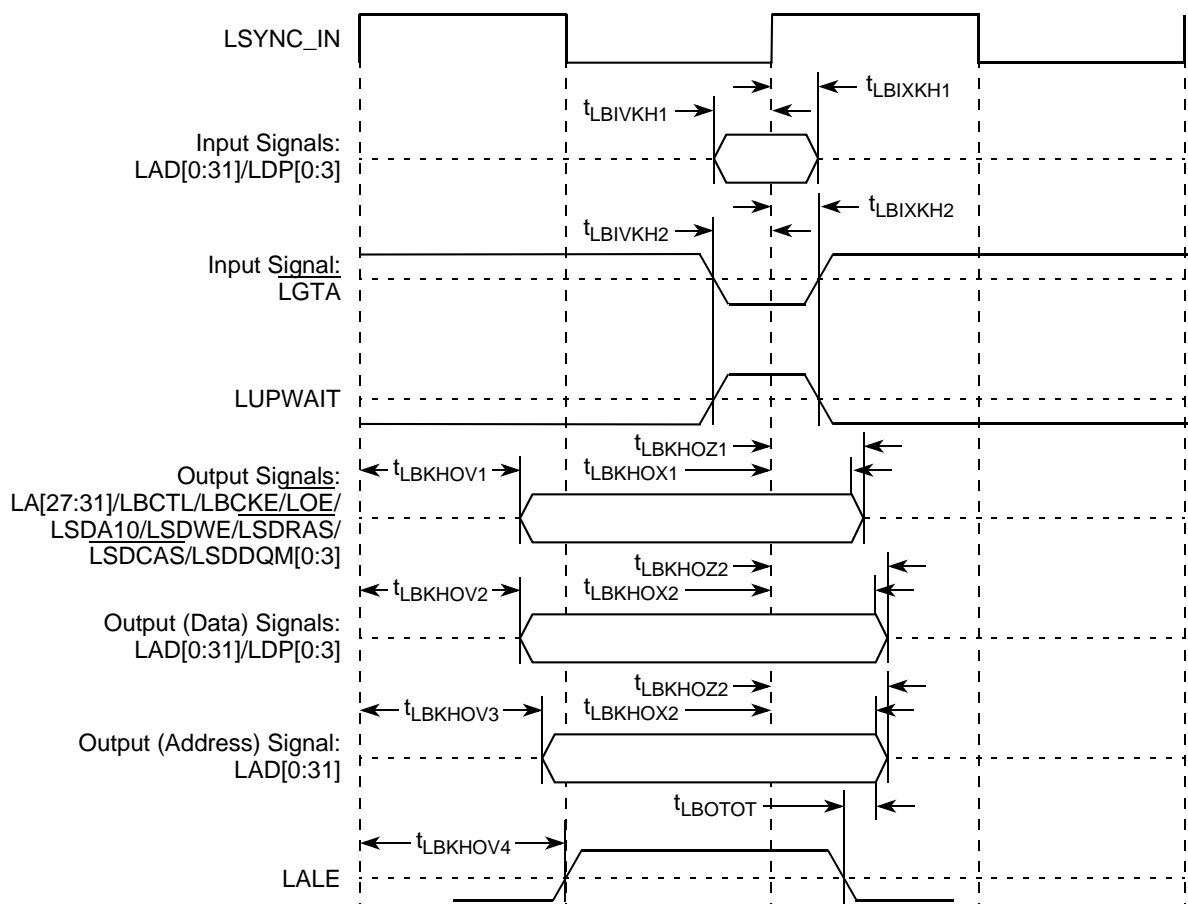Figure 23 through Figure 28 show the local bus signals.

Figure 23. Local Bus Signals (PLL Enabled)

This table describes the timing parameters of the local bus interface at $BV_{DD} = 3.3$ V with PLL disabled.

Table 42. Local Bus Timing Parameters—PLL Bypassed

Parameter	Symbol[1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	12	—	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t_{LBKHKT}	2.3	4.4	ns	8
Input setup to local bus clock (except $\overline{LGTA}$/LUPWAIT)	$t_{LBIVKH1}$	6.2	—	ns	4, 5
$\overline{LGTA}$/LUPWAIT input setup to local bus clock	$t_{LBIVKL2}$	6.1	—	ns	4, 5
Input hold from local bus clock (except $\overline{LGTA}$/LUPWAIT)	$t_{LBIXKH1}$	−1.8	—	ns	4, 5

Table 53. PCI-X AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol	Min	Max	Unit	Notes
$\overline{\text{HRESET}}$ to PCI-X initialization pattern hold time	t_{PCRHIX}	0	50	ns	6, 11

Notes:

1. See the timing measurement conditions in the *PCI-X 1.0a Specification*.

2. Minimum times are measured at the package pin (not the test point). Maximum times are measured with the test point and load circuit.

3. Setup time for point-to-point signals applies to $\overline{\text{REQ}}$ and $\overline{\text{GNT}}$ only. All other signals are bused.

4. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

5. Setup time applies only when the device is not driving the pin. Devices cannot drive and receive signals at the same time.

6. Maximum value is also limited by delay to the first transaction (time for $\overline{\text{HRESET}}$ high to first configuration access, t_{PCRHFV}). The PCI-X initialization pattern control signals after the rising edge of $\overline{\text{HRESET}}$ must be negated no later than two clocks before the first $\overline{\text{FRAME}}$ and must be floated no later than one clock before $\overline{\text{FRAME}}$ is asserted.

7. A PCI-X device is permitted to have the minimum values shown for t_{PCKHOV} and t_{CYC} only in PCI-X mode. In conventional mode, the device must meet the requirements specified in PCI 2.2 for the appropriate clock frequency.

8. Device must meet this specification independent of how many outputs switch simultaneously.

9. The timing parameter t_{PCRHFV} is a minimum of 10 clocks rather than the minimum of 5 clocks in the *PCI-X 1.0a Specification*.

10. Guaranteed by characterization.

11. Guaranteed by design.

This table provides the PCI-X AC timing specifications at 133 MHz. Note that the maximum PCI-X frequency in synchronous mode is 110 MHz.

Table 54. PCI-X AC Timing Specifications at 133 MHz

Parameter	Symbol	Min	Max	Unit	Notes
SYSCLK to signal valid delay	t_{PCKHOV}	—	3.8	ns	1, 2, 3, 7, 8
Output hold from SYSCLK	t_{PCKHOX}	0.7	—	ns	1, 11
SYSCLK to output high impedance	t_{PCKHOZ}	—	7	ns	1, 4, 8, 12
Input setup time to SYSCLK	t_{PCIVKH}	1.2	—	ns	3, 5, 9, 11
Input hold time from SYSCLK	t_{PCIXKH}	0.5	—	ns	11
$\overline{\text{REQ64}}$ to $\overline{\text{HRESET}}$ setup time	t_{PCRVRH}	10	—	clocks	12
$\overline{\text{HRESET}}$ to $\overline{\text{REQ64}}$ hold time	t_{PCRHRX}	0	50	ns	12
$\overline{\text{HRESET}}$ high to first $\overline{\text{FRAME}}$ assertion	t_{PCRHFV}	10	—	clocks	10, 12
PCI-X initialization pattern to $\overline{\text{HRESET}}$ setup time	t_{PCIVRH}	10	—	clocks	12

MPC8548E PowerQUICC III Integrated Processor Hardware Specifications, Rev. 9

— The SD_REF_CLK and $\overline{\text{SD\_REF\_CLK}}$ are internally AC-coupled differential inputs as shown in Figure 39. Each differential clock input (SD_REF_CLK or $\overline{\text{SD\_REF\_CLK}}$) has a 50-Ω termination to SGND_SRDS*n* (xcorevss) followed by on-chip AC-coupling.

— The external reference clock driver must be able to drive this termination.

— The SerDes reference clock input can be either differential or single-ended. See the differential mode and single-ended mode description below for further detailed requirements.

- The maximum average current requirement that also determines the common mode voltage range:

— When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (see the following bullet for more detail), since the input is AC-coupled on-chip.

— This current limitation sets the maximum common mode input voltage to be less than 0.4 V (0.4 V/50 = 8 mA) while the minimum common mode input level is 0.1 V above SGND_SRDS*n* (xcorevss). For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 to 16 mA (0–0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.

— If the device driving the SD_REF_CLK and $\overline{\text{SD\_REF\_CLK}}$ inputs cannot drive 50 Ω to SGND_SRDS*n* (xcorevss) DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.

- The input amplitude requirement:

— This requirement is described in detail in the following sections.
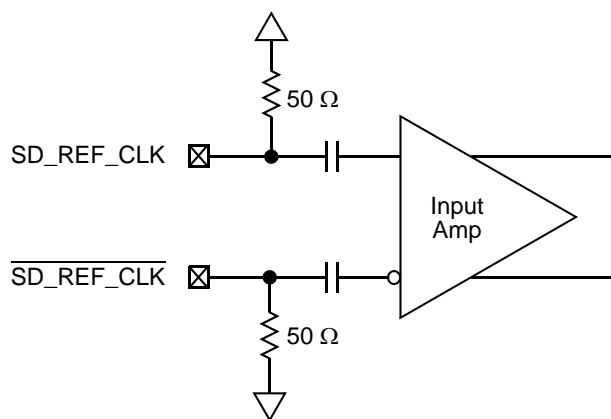

Figure 39. Receiver of SerDes Reference Clocks

16.2.2 DC Level Requirement for SerDes Reference Clocks

The DC level requirement for the SerDes reference clock inputs is different depending on the signaling mode used to connect the clock driver chip and SerDes reference clock inputs as described below:

- Differential mode

to AC-coupling. Its value could be ranged from 140 to 240 Ω depending on the clock driver vendor's requirement. R2 is used together with the SerDes reference clock receiver's 50-Ω termination resistor to attenuate the LVPECL output's differential peak level such that it meets the SerDes reference clock's differential input amplitude requirement (between 200 and 800 mV differential peak). For example, if the LVPECL output's differential peak is 900 mV and the desired SerDes reference clock input amplitude is selected as 600 mV, the attenuation factor is 0.67, which requires R2 = 25 Ω. Consult a clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.
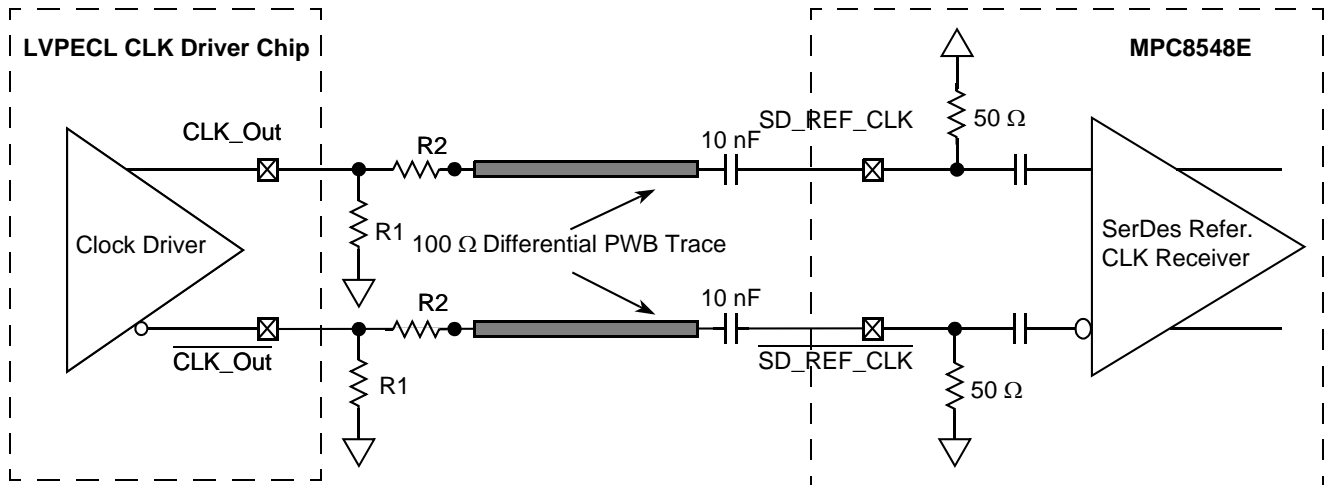

Figure 45. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

Figure 46 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with the SerDes reference clock input's DC requirement.
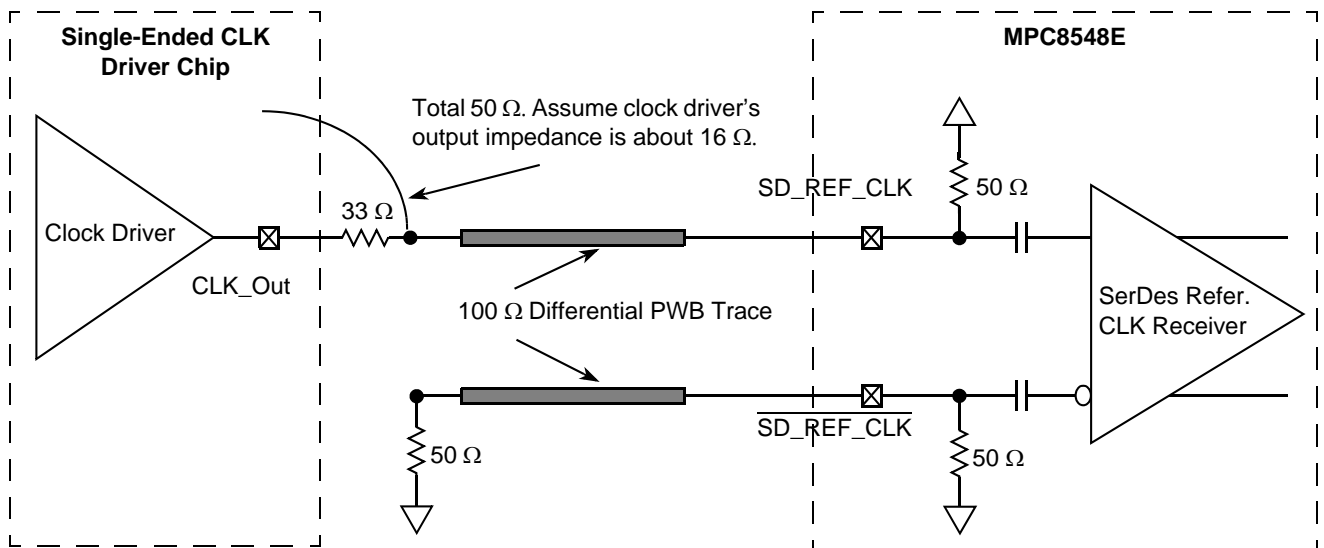

Figure 46. Single-Ended Connection (Reference Only)

Table 57. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$V_{RX\text{-}CM\text{-}ACp}$	AC peak common mode input voltage	—	—	150	mV	$V_{RX\text{-}CM\text{-}ACp} = |V_{RXD+} - V_{RXD\text{-}}|/2 + V_{RX\text{-}CM\text{-}DC}$ $V_{RX\text{-}CM\text{-}DC} = DC_{(avg)}$ of $|V_{RX\text{-}D+} + V_{RX\text{-}D\text{-}}| \div 2$. See Note 2.
$RL_{RX\text{-}DIFF}$	Differential return loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at +300 mV and –300 mV, respectively. See Note 4.
$RL_{RX\text{-}CM}$	Common mode return loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D– lines biased at 0 V. See Note 4.
$Z_{RX\text{-}DIFF\text{-}DC}$	DC differential input impedance	80	100	120	Ω	RX DC differential mode impedance. See Note 5.
$Z_{RX\text{-}DC}$	DC input impedance	40	50	60	Ω	Required RX D+ as well as D– DC impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX\text{-}HIGH\text{-}IMP\text{-}DC}$	Powered down DC input impedance	200 k	—	—	Ω	Required RX D+ as well as D– DC impedance when the receiver terminations do not have power. See Note 6.
$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$	Electrical idle detect threshold	65	—	175	mV	$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p} = 2 \times |V_{RX\text{-}D+} - V_{RX\text{-}D\text{-}}|$. Measured at the package pins of the receiver
$T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERTIME}$	Unexpected electrical idle enter detect threshold integration time	—	—	10	ms	An unexpected electrical idle ($V_{RX\text{-}DIFFp\text{-}p} < V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$) must be recognized no longer than $T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERING}$ to signal an unexpected idle condition.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50-Ω probes—see Figure 50). Note that the series capacitors, CTX, are optional for the return loss measurement.
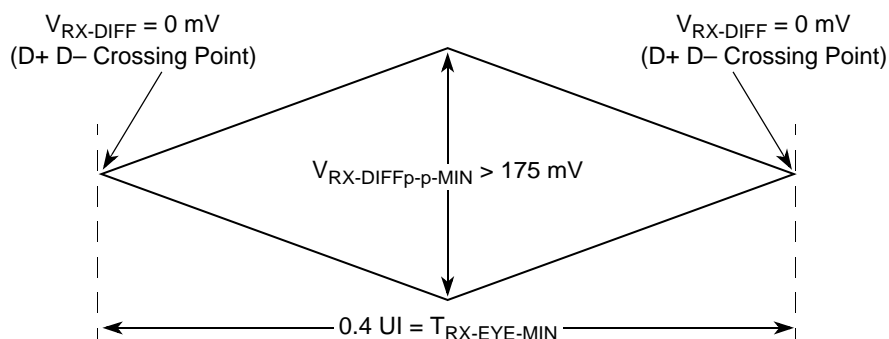
Figure 49. Minimum Receiver Eye Timing and Voltage Compliance Specification

17.5.1   Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in Figure 50.

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D– not being exactly matched in length at the package pin boundary.

Figure 50. Compliance Test/Measurement Load

Table 60. Short Run Transmitter AC Timing Specifications—2.5 GBaud

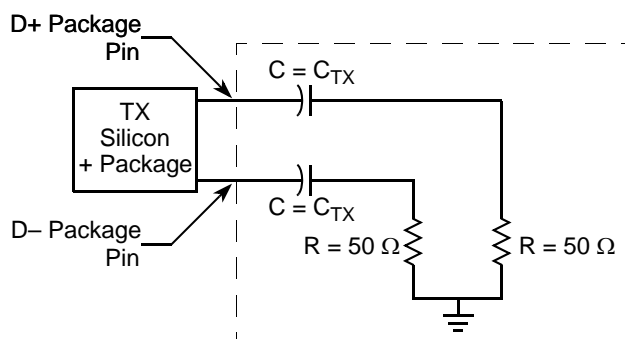| Characteristic	Symbol	Range		Unit	Notes
		Min	**Max**		
Output voltage	V_O	−0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	500	1000	mV p-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	400	400	ps	±100 ppm

Table 61. Short Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	**Max**		
Output voltage	V_O	−0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	500	1000	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	320	320	ps	±100 ppm

Table 62. Long Run Transmitter AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	**Max**		
Output voltage	V_O	−0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	800	1600	mVp-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit interval	UI	800	800	ps	±100 ppm

MPC8548E PowerQUICC III Integrated Processor Hardware Specifications, Rev. 9

802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE Std. 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

18.9.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for template measurements is the continuous jitter test pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12}. The eye pattern shall be measured with AC coupling and the compliance template centered at 0 V differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100-Ω resistive ± 5% differential to 2.5 GHz.

18.9.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (baud frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter test pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 V differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

18.9.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive ± 5% differential to 2.5 GHz.

18.9.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in Section 18.7, "Receiver Specifications," and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 54 and Table 69. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 18.7, "Receiver Specifications," is then added to the signal and the test load is replaced by the receiver being tested.

Notes:

1. All dimensions are in millimeters.
2. Dimensioning and tolerancing per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement shall exclude any effect of mark on top surface of package.
6. All dimensions are symmetric across the package center lines unless dimensioned otherwise.

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{MWE}}$	E7	O	GV$_{DD}$	—
$\overline{\text{MCAS}}$	H7	O	GV$_{DD}$	—
$\overline{\text{MRAS}}$	L8	O	GV$_{DD}$	—
MCKE[0:3]	F10, C10, J11, H11	O	GV$_{DD}$	11
$\overline{\text{MCS}}$[0:3]	K8, J8, G8, F8	O	GV$_{DD}$	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV$_{DD}$	—
$\overline{\text{MCK}}$[0:5]	J9, A15, G1, L9, B14, F2	O	GV$_{DD}$	—
MODT[0:3]	E6, K6, L7, M7	O	GV$_{DD}$	—
MDIC[0:1]	A19, B19	I/O	GV$_{DD}$	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV$_{DD}$	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV$_{DD}$	—
LA[27]	H21	O	BV$_{DD}$	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV$_{DD}$	5, 7, 9
$\overline{\text{LCS}}$[0:4]	J25, C20, J24, G26, A26	O	BV$_{DD}$	
$\overline{\text{LCS5}}$/DMA_DREQ2	D23	I/O	BV$_{DD}$	1
$\overline{\text{LCS6}}$/DMA_DACK2	G20	O	BV$_{DD}$	1
$\overline{\text{LCS7}}$/$\overline{\text{DMA\_DDONE2}}$	E21	O	BV$_{DD}$	1
$\overline{\text{LWE0}}$/$\overline{\text{LBS0}}$/LSDDQM[0]	G25	O	BV$_{DD}$	5, 9
$\overline{\text{LWE1}}$/$\overline{\text{LBS1}}$/LSDDQM[1]	C23	O	BV$_{DD}$	5, 9
$\overline{\text{LWE2}}$/$\overline{\text{LBS2}}$/LSDDQM[2]	J21	O	BV$_{DD}$	5, 9
$\overline{\text{LWE3}}$/$\overline{\text{LBS3}}$/LSDDQM[3]	A24	O	BV$_{DD}$	5, 9
LALE	H24	O	BV$_{DD}$	5, 8, 9
LBCTL	G27	O	BV$_{DD}$	5, 8, 9
LGPL0/LSDA10	F23	O	BV$_{DD}$	5, 9
LGPL1/$\overline{\text{LSDWE}}$	G22	O	BV$_{DD}$	5, 9
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LSDRAS}}$	B27	O	BV$_{DD}$	5, 8, 9
LGPL3/$\overline{\text{LSDCAS}}$	F24	O	BV$_{DD}$	5, 9
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/LPBSE	H23	I/O	BV$_{DD}$	—
LGPL5	E26	O	BV$_{DD}$	5, 9
LCKE	E24	O	BV$_{DD}$	—
LCLK[0:2]	E23, D24, H22	O	BV$_{DD}$	—

MPC8548E PowerQUICC III Integrated Processor Hardware Specifications, Rev. 9

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DFT				
L1_TSTCLK	AC25	I	OV_{DD}	25
L2_TSTCLK	AE22	I	OV_{DD}	25
LSSD_MODE	AH20	I	OV_{DD}	25
TEST_SEL	AH14	I	OV_{DD}	25
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV_{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV_{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV_{DD}	—
LV_{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV_{DD}	—
TV_{DD}	W9, Y6	Power for TSEC3 and TSEC4 (2,5 V, 3.3 V)	TV_{DD}	—
GV_{DD}	B3, B11, C7, C9, C14, C17, D4, D6, D10, D15, E2, E8, E11, E18, F5, F12, F16, G3, G7, G9, G11, H5, H12, H15, H17, J10, K3, K12, K16, K18, L6, M4, M8, M13	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV_{DD}	—

MPC8548E PowerQUICC III Integrated Processor Hardware Specifications, Rev. 9

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SD_PLL_TPA	U26	O	—	24

Note: All note references in this table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 73 provides the pin-out listing for the MPC8545E 783 FC-PBGA package.

NOTE

All note references in the following table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 73. MPC8545E Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1 and PCI2 (One 64-Bit or Two 32-Bit)				
PCI1_AD[63:32]/PCI2_AD[31:0]	AB14, AC15, AA15, Y16, W16, AB16, AC16, AA16, AE17, AA18, W18, AC17, AD16, AE16, Y17, AC18, AB18, AA19, AB19, AB21, AA20, AC20, AB20, AB22, AC22, AD21, AB23, AF23, AD23, AE23, AC23, AC24	I/O	OV$_{DD}$	17
PCI1_AD[31:0]	AH6, AE7, AF7, AG7, AH7, AF8, AH8, AE9, AH9, AC10, AB10, AD10, AG10, AA10, AH10, AA11, AB12, AE12, AG12, AH12, AB13, AA12, AC13, AE13, Y14, W13, AG13, V14, AH13, AC14, Y15, AB15	I/O	OV$_{DD}$	17
PCI1_C_$\overline{BE}$[7:4]/PCI2_C_$\overline{BE}$[3:0]	AF15, AD14, AE15, AD15	I/O	OV$_{DD}$	17
PCI1_C_$\overline{BE}$[3:0]	AF9, AD11, Y12, Y13	I/O	OV$_{DD}$	17
PCI1_PAR64/PCI2_PAR	W15	I/O	OV$_{DD}$	—
$\overline{PCI1\_GNT}$[4:1]	AG6, AE6, AF5, AH5	O	OV$_{DD}$	5, 9, 35
$\overline{PCI1\_GNT0}$	AG5	I/O	OV$_{DD}$	—
$\overline{PCI1\_IRDY}$	AF11	I/O	OV$_{DD}$	2
PCI1_PAR	AD12	I/O	OV$_{DD}$	—
$\overline{PCI1\_PERR}$	AC12	I/O	OV$_{DD}$	2
$\overline{PCI1\_SERR}$	V13	I/O	OV$_{DD}$	2, 4
$\overline{PCI1\_STOP}$	W12	I/O	OV$_{DD}$	2
$\overline{PCI1\_TRDY}$	AG11	I/O	OV$_{DD}$	2
$\overline{PCI1\_REQ}$[4:1]	AH2, AG4, AG3, AH4	I	OV$_{DD}$	—
$\overline{PCI1\_REQ0}$	AH3	I/O	OV$_{DD}$	—
PCI1_CLK	AH26	I	OV$_{DD}$	39
$\overline{PCI1\_DEVSEL}$	AH11	I/O	OV$_{DD}$	2

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
IIC1_SDA	AG21	I/O	OV$_{DD}$	4, 27
IIC2_SCL	AG15	I/O	OV$_{DD}$	4, 27
IIC2_SDA	AG14	I/O	OV$_{DD}$	4, 27
SerDes				
SD_RX[0:7]	M28, N26, P28, R26, W26, Y28, AA26, AB28	I	XV$_{DD}$	—
$\overline{\text{SD\_RX}}$[0:7]	M27, N25, P27, R25, W25, Y27, AA25, AB27	I	XV$_{DD}$	—
SD_TX[0:7]	M22, N20, P22, R20, U20, V22, W20, Y22	O	XV$_{DD}$	—
$\overline{\text{SD\_TX}}$[0:7]	M23, N21, P23, R21, U21, V23, W21, Y23	O	XV$_{DD}$	—
SD_PLL_TPD	U28	O	XV$_{DD}$	24
SD_REF_CLK	T28	I	XV$_{DD}$	—
$\overline{\text{SD\_REF\_CLK}}$	T27	I	XV$_{DD}$	—
Reserved	AC1, AC3	—	—	2
Reserved	M26, V28	—	—	32
Reserved	M25, V27	—	—	34
Reserved	M20, M21, T22, T23	—	—	38
General-Purpose Output				
GPOUT[24:31]	K26, K25, H27, G28, H25, J26, K24, K23	O	BV$_{DD}$	—
System Control				
$\overline{\text{HRESET}}$	AG17	I	OV$_{DD}$	—
$\overline{\text{HRESET\_REQ}}$	AG16	O	OV$_{DD}$	29
$\overline{\text{SRESET}}$	AG20	I	OV$_{DD}$	—
$\overline{\text{CKSTP\_IN}}$	AA9	I	OV$_{DD}$	—
$\overline{\text{CKSTP\_OUT}}$	AA8	O	OV$_{DD}$	2, 4
Debug				
TRIG_IN	AB2	I	OV$_{DD}$	—
TRIG_OUT/READY/$\overline{\text{QUIESCE}}$	AB1	O	OV$_{DD}$	6, 9, 19, 29
MSRCID[0:1]	AE4, AG2	O	OV$_{DD}$	5, 6, 9
MSRCID[2:4]	AF3, AF1, AF2	O	OV$_{DD}$	6, 19, 29
MDVAL	AE5	O	OV$_{DD}$	6
CLK_OUT	AE21	O	OV$_{DD}$	11
Clock				
RTC	AF16	I	OV$_{DD}$	—
SYSCLK	AH17	I	OV$_{DD}$	—

MPC8548E PowerQUICC III Integrated Processor Hardware Specifications, Rev. 9

20 Clocking

This section describes the PLL configuration of the device. Note that the platform clock is identical to the core complex bus (CCB) clock.

20.1 Clock Ranges

Table 75 through Table 77 provide the clocking specifications for the processor cores and Table 78, through Table 80 provide the clocking specifications for the memory bus.

Table 75. Processor Core Clocking Specifications (MPC8548E and MPC8547E)

Characteristic	Maximum Processor Core Frequency						Unit	Notes
	1000 MHz		1200 MHz		1333 MHz			
	Min	Max	Min	Max	Min	Max		
e500 core processor frequency	800	1000	800	1200	800	1333	MHz	1, 2

Notes:

1. **Caution:** The CCB to SYSCLK ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. See Section 20.2, "CCB/SYSCLK PLL Ratio," and Section 20.3, "e500 Core PLL Ratio," for ratio settings.
2.)The minimum e500 core frequency is based on the minimum platform frequency of 333 MHz.

Table 76. Processor Core Clocking Specifications (MPC8545E)

Characteristic	Maximum Processor Core Frequency						Unit	Notes
	800 MHz		1000 MHz		1200 MHz			
	Min	Max	Min	Max	Min	Max		
e500 core processor frequency	800	800	800	1000	800	1200	MHz	1, 2

Notes:

1. **Caution:** The CCB to SYSCLK ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. See Section 20.2, "CCB/SYSCLK PLL Ratio," and Section 20.3, "e500 Core PLL Ratio," for ratio settings.
2.)The minimum e500 core frequency is based on the minimum platform frequency of 333 MHz.

20.3   e500 Core PLL Ratio

This table describes the clock ratio between the e500 core complex bus (CCB) and the e500 core clock. This ratio is determined by the binary value of LBCTL, LALE, and LGPL2 at power up, as shown in this table.

Table 82. e500 Core to CCB Clock Ratio

Binary Value of LBCTL, LALE, LGPL2 Signals	e500 core:CCB Clock Ratio	Binary Value of LBCTL, LALE, LGPL2 Signals	e500 core:CCB Clock Ratio
000	4:1	100	2:1
001	9:2	101	5:2
010	Reserved	110	3:1
011	3:2	111	7:2

20.4   Frequency Options

Table 83This table shows the expected frequency values for the platform frequency when using a CCB clock to SYSCLK ratio in comparison to the memory bus clock speed.

Table 83. Frequency Options of SYSCLK with Respect to Memory Bus Speeds

CCB to SYSCLK Ratio	SYSCLK (MHz)								
	16.66	25	33.33	41.66	66.66	83	100	111	133.33
	Platform/CCB Frequency (MHz)								
2									
3								333	400
4						333	400	445	533
5					333	415	500		
6					400	500			
8				333	533				
9				375					
10			333	417					
12			400	500					
16		400	533						
20	333	500							

Note: Due to errata Gen 13 the max sys clk frequency must not exceed 100 MHz if the core clk frequency is below 1200 MHz.

22.10 Guidelines for High-Speed Interface Termination

This section provides the guidelines for high-speed interface termination when the SerDes interface is entirely unused and when it is partly unused.

22.10.1 SerDes Interface Entirely Unused

If the high-speed SerDes interface is not used at all, the unused pin must be terminated as described in this section.

The following pins must be left unconnected (float):

- SD_TX[7:0]
- $\overline{\text{SD\_TX}}$[7:0]
- Reserved pins T22, T23, M20, M21

The following pins must be connected to GND:

- SD_RX[7:0]
- $\overline{\text{SD\_RX}}$[7:0]
- SD_REF_CLK
- $\overline{\text{SD\_REF\_CLK}}$

NOTE

It is recommended to power down the unused lane through SRDSCR1[0:7] register (offset = 0xE_0F08) (This prevents the oscillations and holds the receiver output in a fixed state.) that maps to SERDES lane 0 to lane 7 accordingly.

Pins V28 and M26 must be tied to XV_{DD}. Pins V27 and M25 must be tied to GND through a 300-Ω resistor.

In Rev 2.0 silicon, POR configuration pin cfg_srds_en on TSEC4_TXD[2]/TSEC3_TXD[6] can be used to power down SerDes block.

22.10.2 SerDes Interface Partly Unused

If only part of the high-speed SerDes interface pins are used, the remaining high-speed serial I/O pins must be terminated as described in this section.

The following pins must be left unconnected (float) if not used:

- SD_TX[7:0]
- $\overline{\text{SD\_TX}}$[7:0]
- Reserved pins: T22, T23, M20, M21

The following pins must be connected to GND if not used:

- SD_RX[7:0]
- $\overline{\text{SD\_RX}}$[7:0]
- SD_REF_CLK

23 Ordering Information

Ordering information for the parts fully covered by this specification document is provided in
Section 23.1, "Part Numbers Fully Addressed by this Document."

## 23.1 Part Numbers Fully Addressed by this Document

This table provides the Freescale part numbering nomenclature for the device. Note that the individual part
numbers correspond to a maximum processor core frequency. For available frequencies, contact your local
Freescale sales office. In addition to the processor frequency, the part-numbering scheme also includes an
application modifier that may specify special application conditions. Each part number also contains a
revision code that refers to the die mask revision number.

Table 87. Part Numbering Nomenclature

MPC	*nnnnn*	*t*	*pp*	*ff*	*c*	*r*
Product Code	Part Identifier	Temperature	Package[1, 2, 3]	Processor Frequency[4]	Core Frequency	Silicon Version
MPC	8548E	Blank = 0 to 105°C C = −40° to 105°C	HX = CBGA VU = Pb-free CBGA PX = PBGA VT = Pb-free PBGA	AV = 1500[3] AU = 1333 AT = 1200 AQ = 1000	J = 533 H = 500[5] G = 400	Blank = Ver. 2.0 (SVR = 0x80390020) A = Ver. 2.1.1 B = Ver. 2.1.2 C = Ver. 2.1.3 (SVR = 0x80390021) D = Ver. 3.1.x (SVR = 0x80390031)
	8548					Blank = Ver. 2.0 (SVR = 0x80310020) A = Ver. 2.1.1 B = Ver. 2.1.2 C = Ver. 2.1.3 (SVR = 0x80310021) D = Ver. 3.1.x (SVR = 0x80310031)
	8547E			AU = 1333 AT = 1200 AQ = 1000	J = 533 G = 400	Blank = Ver. 2.0 (SVR = 0x80390120) A = Ver. 2.1.1 B = Ver. 2.1.2 C = Ver. 2.1.3 (SVR = 0x80390121) D = Ver. 3.1.x (SVR = 0x80390131)
	8547					Blank = Ver. 2.0 (SVR = 0x80390120) A = Ver. 2.1.1 B = Ver. 2.1.2 C = Ver. 2.1.3 (SVR = 0x80310121) D = Ver. 3.1.x (SVR = 0x80310131)

23.2 Part Marking

Parts are marked as the example shown in Figure 64.

(F)
MPC8548xxxxxx
TWLYWW
MMMMM CCCCC
YWWLAZ
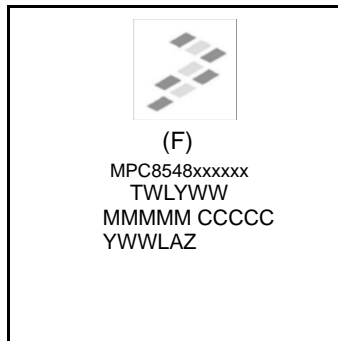
Notes:

TWLYYWW is final test traceability code.
MMMMM is 5 digit mask number.
CCCCC is the country of assembly. This space is left blank if parts are assembled in the United States.
YWWLAZ is assembly traceability code.

Figure 64. Part Marking for CBGA and PBGA Device